Model: ST1000LM024 HN-M
S/N: S32XJ9AG633292

Disk Erasure Report

Page 1 - Erasure Status

Organisation Performing The Disk Erasure

Business Name: **Adam Matthiesen Support Center**

Business Address: **https://matthiesen.xyz**

Contact Name: **IT Support**   Contact Phone: **support@matthiesen.xyz**

Customer Details

Name: **General Sale**

Address:

Contact Name: Contact Phone:

Disk Information

Make/Model: **ST1000LM024 HN-M**   Serial: **S32XJ9AG633292**

Size(Apparent): **1000 GB, 1000203804160 bytes**   Bus: **USB**

Size(Real): **1000 GB, 1000203804160 bytes**

Disk Erasure Details

Start time: **2023/12/20 04:50:56**   End time: **2023/12/21 00:47:12**

Duration: **19:56:16**   Status: **ERASED**   **See Warning !**

Method: **DoD Short**   PRNG algorithm: **Isaac64**

Final Pass(Zeros/Ones/None): **Zeros**   Verify Pass(Last/All/None): **Verify Last**

*Bytes Erased: **1000203804160, (100.00%)**   Rounds(completed/requested): **1/1**

HPA/DCO: **Unknown**   HPA/DCO Size: **Unknown**

Errors(pass/sync/verify): **0/0/0**   Throughput: **69 MB/sec**
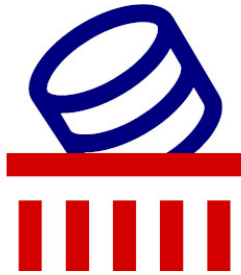
Information: **Warning**   **HPA/DCO data unavailable, can not determine hidden sector status.**

* bytes erased: The amount of drive that's been erased at least once

Technician/Operator ID   Signature:

Name/ID: **Adam M.**

```
smartctl 7.3 2022-02-28 r5338 [x86_64-linux-6.1.0-13-amd64] (local build)
copyright (c) 2002-22, bruce allen, christian franke, www.smartmontools.org

=== start of information section ===
model family:     Seagate Samsung SpinPoint M8 (AF)
device model:     ST1000LM024 HN-M101MBB
serial number:    S32XJ9AG633292
lu wwn device id: 5 0004cf 20ff62677
firmware version: 2BA30001
user capacity:    1,000,203,804,160 bytes [1.00 TB]
sector sizes:     512 bytes logical, 4096 bytes physical
rotation rate:    5400 rpm
form factor:      2.5 inches
device is:        In smartctl database 7.3/5319
ata version is:   ATA8-ACS T13/1699-D revision 6
sata version is:  SATA 3.0, 6.0 Gb/s (current: 6.0 Gb/s)
local time is:    Thu Dec 21 09:04:31 2023 PST
smart support is: Available - device has SMART capability.
smart support is: Enabled

=== start of read smart data section ===
smart status not supported: Incomplete response, ATA output registers missing
smart overall-health self-assessment test result: PASSED
warning: This result is based on an Attribute check.


general smart values:
offline data collection status:  (0x00)Offline data collection activity
was never started.
auto offline data collection: Disabled.
self-test execution status:      (   0)The previous self-test routine completed
without error or no self-test has ever
been run.
total time to complete offline
data collection: (12300) seconds.
offline data collection
capabilities:  (0x5b) SMART execute Offline immediate.
auto offline data collection on/off support.
suspend offline collection upon new
command.
offline surface scan supported.
self-test supported.
no conveyance self-test supported.
selective self-test supported.
smart capabilities:            (0x0003)Saves SMART data before entering
power-saving mode.
supports smart auto save timer.
error logging capability:        (0x01)Error logging supported.
general purpose logging supported.
short self-test routine
recommended polling time: (   2) minutes.
extended self-test routine
recommended polling time:  ( 205) minutes.
sct capabilities:        (0x003f)SCT Status supported.
sct error recovery control supported.
sct feature control supported.
sct data table supported.

smart attributes data structure revision number: 16
vendor specific smart attributes with thresholds:
```

id#	attribute_name	flag	value	worst	thresh	type	updated	when_failed	raw_value
1	raw_read_error_rate	0x002f	100	100	051	pre-fail	always	–	5
2	throughput_performance	0x0026	252	252	000	old_age	always	–	0
3	spin_up_time	0x0023	092	091	025	pre-fail	always	–	2469
4	start_stop_count	0x0032	100	100	000	old_age	always	–	576

```
  5 reallocated_sector_ct   0x0033  252  252  010  pre-fail  always   -   0
  7 seek_error_rate         0x002e  252  252  051  old_age   always   -   0
  8 seek_time_performance   0x0024  252  252  015  old_age   offline  -   0
  9 power_on_hours          0x0032  100  100  000  old_age   always   -   11037
 10 spin_retry_count        0x0032  252  252  051  old_age   always   -   0
 12 power_cycle_count       0x0032  100  100  000  old_age   always   -   586
191 g-sense_error_rate      0x0022  100  100  000  old_age   always   -   31
192 power-off_retract_count 0x0022  100  100  000  old_age   always   -   31
194 temperature_celsius     0x0002  064  058  000  old_age   always   -   29 (min/max 14/42)
195 hardware_ecc_recovered  0x003a  100  100  000  old_age   always   -   0
196 reallocated_event_count 0x0032  252  252  000  old_age   always   -   0
197 current_pending_sector  0x0032  252  252  000  old_age   always   -   0
198 offline_uncorrectable   0x0030  252  252  000  old_age   offline  -   0
199 udma_crc_error_count    0x0036  100  100  000  old_age   always   -   74
200 multi_zone_error_rate   0x002a  100  100  000  old_age   always   -   31676
223 load_retry_count        0x0032  097  097  000  old_age   always   -   3071
225 load_cycle_count        0x0032  077  077  000  old_age   always   -   238281

smart error log version: 1
ata error count: 878 (device log contains only the most recent five errors)
cr = command register [hex]
fr = features register [hex]
sc = sector count register [hex]
sn = sector number register [hex]
cl = cylinder low register [hex]
ch = cylinder high register [hex]
dh = device/head register [hex]
dc = device command register [hex]
er = error register [hex]
st = status register [hex]
powered_up_time is measured from power on, and printed as
ddd+hh:mm:SS.sss where DD=days, hh=hours, mm=minutes,
ss=sec, and sss=millisec. it "wraps" after 49.710 days.

error 878 occurred at disk power-on lifetime: 311 hours (12 days + 23 hours)
  when the command that caused the error occurred, the device was active or idle.

  after command completion occurred, registers were:
  er st sc sn cl ch dh
  -- -- -- -- -- -- --
  40 51 00 00 00 00 40

  commands leading to the command that caused the error were:
  cr fr sc sn cl ch dh dc   powered_up_time  command/feature_name
  -- -- -- -- -- -- -- --   ---------------  --------------------
  01 9f 18 9f 18 f0 18 9f      10:54:18.685  [RESERVED]
  00 00 00 00 00 00 00 00      00:00:01.803  NOP [Abort queued commands]
  61 00 08 60 37 ae 40 00      00:00:01.859  WRITE FPDMA QUEUED
  61 00 08 38 cf 6c 40 00      00:00:01.859  WRITE FPDMA QUEUED
  61 00 08 58 1f ae 40 00      00:00:01.859  WRITE FPDMA QUEUED

error 877 occurred at disk power-on lifetime: 311 hours (12 days + 23 hours)
  when the command that caused the error occurred, the device was active or idle.

  after command completion occurred, registers were:
  er st sc sn cl ch dh
  -- -- -- -- -- -- --
  40 51 00 00 00 00 40

  commands leading to the command that caused the error were:
  cr fr sc sn cl ch dh dc   powered_up_time  command/feature_name
  -- -- -- -- -- -- -- --   ---------------  --------------------
  01 9f 18 9f 18 f0 18 9f      10:54:18.685  [RESERVED]
  00 00 00 00 00 00 00 00      00:00:01.802  NOP [Abort queued commands]
```

```
 61 00 50 70 72 6e 40 00        00:00:01.828  WRITE FPDMA QUEUED
 ea 00 00 00 00 00 e0 00        00:00:01.827  FLUSH CACHE EXT
 61 00 10 68 cf 6c 40 00        00:00:01.827  WRITE FPDMA QUEUED

error 876 occurred at disk power-on lifetime: 311 hours (12 days + 23 hours)
  when the command that caused the error occurred, the device was active or idle.

  after command completion occurred, registers were:
  er st sc sn cl ch dh
  -- -- -- -- -- -- --
  40 51 00 00 00 00 e0

  commands leading to the command that caused the error were:
  cr fr sc sn cl ch dh dc    powered_up_time  command/feature_name
  -- -- -- -- -- -- -- --    ---------------  --------------------
  01 9f 18 9f 18 f0 18 9f       10:54:18.685  [RESERVED]
  00 00 00 00 00 00 00 00       00:00:01.510  NOP [Abort queued commands]
  61 00 00 40 3d 52 40 00       00:00:01.522  WRITE FPDMA QUEUED
  61 00 10 58 cf 6c 40 00       00:00:01.522  WRITE FPDMA QUEUED
  61 00 80 e8 e4 d7 40 00       00:00:01.522  WRITE FPDMA QUEUED

error 875 occurred at disk power-on lifetime: 311 hours (12 days + 23 hours)
  when the command that caused the error occurred, the device was active or idle.

  after command completion occurred, registers were:
  er st sc sn cl ch dh
  -- -- -- -- -- -- --
  40 51 00 00 00 00 40

  commands leading to the command that caused the error were:
  cr fr sc sn cl ch dh dc    powered_up_time  command/feature_name
  -- -- -- -- -- -- -- --    ---------------  --------------------
  01 9f 18 9f 18 f0 18 9f       10:54:18.685  [RESERVED]
  00 00 00 00 00 00 00 00       00:00:01.361  NOP [Abort queued commands]
  61 00 80 00 88 88 40 00       00:00:01.397  WRITE FPDMA QUEUED
  61 00 10 60 cf 6c 40 00       00:00:01.397  WRITE FPDMA QUEUED
  61 00 10 d8 cf 6c 40 00       00:00:01.397  WRITE FPDMA QUEUED

error 874 occurred at disk power-on lifetime: 311 hours (12 days + 23 hours)
  when the command that caused the error occurred, the device was active or idle.

  after command completion occurred, registers were:
  er st sc sn cl ch dh
  -- -- -- -- -- -- --
  40 51 00 00 00 00 40

  commands leading to the command that caused the error were:
  cr fr sc sn cl ch dh dc    powered_up_time  command/feature_name
  -- -- -- -- -- -- -- --    ---------------  --------------------
  01 9f 18 9f 18 f0 18 9f       10:54:18.685  [RESERVED]
  00 00 00 00 00 00 00 00       00:00:01.296  NOP [Abort queued commands]
  61 00 28 58 5e 6e 40 00       00:00:01.313  WRITE FPDMA QUEUED
  61 00 08 48 ce 14 40 00       00:00:01.313  WRITE FPDMA QUEUED
  61 00 18 68 9d 29 40 00       00:00:01.313  WRITE FPDMA QUEUED

smart self-test log structure revision number 1
no self-tests have been logged.  [to run self-tests, use: smartctl -t]

smart selective self-test log data structure revision number 0
note: revision number not 1 implies that no selective self-test has ever been run
 span  min_lba  max_lba  current_test_status
    1        0        0  completed [00% left] (0-65535)
    2        0        0  not_testing
    3        0        0  not_testing
```
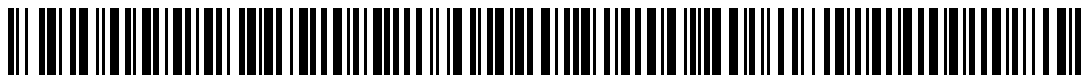
```
    4        0        0  not_testing
    5        0        0  not_testing
selective self-test flags (0x0):
  after scanning selected spans, do not read-scan remainder of disk.
if selective self-test is pending on power-up, resume after 0 minute delay.
```